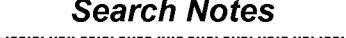


Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/536,512	KIM ET AL.	
	Examiner	Art Unit	
	Sin J. Lee	1795	

## **Search Notes**



**Application/Control No.**

10/536,512

**Examiner**

Sin J. Lee

**Applicant(s)/Patent under  
Reexamination**

KIM ET AL.

## **Art Unit**

1795

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**